



SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION  (PTO-1449)				ATTY. DOCKET NO. 55071-268	SERIAL NO. 10/626,864		
				APPLICANT Xuelong SHI, et al.			
				FILING DATE July 25, 2003	GROUP 2825		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code <sup>1</sup> -Number <sup>1</sup> -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
NL		WO 99/14638	03/25/1999	NUMERICAL TECHNOLOGIES, INC.		Yes	No
						x	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
NL		HEWAK, Daniel., et al. "Fabrication of tapers and lenslike waveguides by a microcontrolled dip coating procedure." Applied Optics, Volume 27, Number 21, November 1, 1988, pp. 4562-4564					
NL		TORRES, J.A., et al. "Contrast-based assist feature optimization photolithography." Optical Microlithography XV, Santa Clara CA, March 5-8 2002, Volume 4691, pp. 179-187, XP 000118756, ISSN: 0277-788X					
EXAMINER Nam			DATE CONSIDERED 11/21/05				

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.